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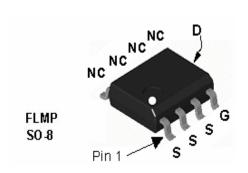
# FDS7288N3 30V N-Channel PowerTrench<sup>®</sup> MOSFET

## **General Description**

This N-Channel MOSFET in the thermally enhanced SO8 FLMP package has been designed specifically to improve the overall efficiency of DC/DC converters. Providing a balance of low  $R_{DS(ON)}$  and Qg it is ideal for synchronous rectifier applications in both isolated and non-isolated topologies. It is also well suited for both high and low side switch applications in Point of Load converters.

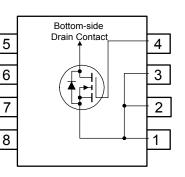
# Applications

- Secondary side Synchronous rectifier
- Synchronous Buck VRM and POL Converters



# Features

- 20.5 A, 30 V  $R_{DS(ON)} = 4.5 \text{ m}\Omega \textcircled{0} V_{GS} = 10 \text{ V}$  $R_{DS(ON)} = 5.6 \text{ m}\Omega \textcircled{0} V_{GS} = 4.5 \text{ V}$
- High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- Low Qg and Rg for fast switching
- SO-8 FLMP for enhanced thermal performance in an industry-standard package outline.



# Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

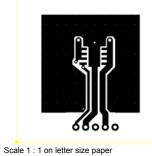
Symbol	Parameter			Ratings	Units
V <sub>DSS</sub>	Drain-Source	ce Voltage		30	V
V <sub>GSS</sub>	Gate-Source Voltage			±20	V
I <sub>D</sub> Drain Current – Continuous		(Note 1a)	20		
		- Pulsed		60	
PD	Power Diss	ipation for Single Operati	ON (Note 1a)	3.0	W
			(Note 1b)	1.5	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		nperature Range	-55 to +150	
Therma	l Charac	teristics			
$R_{ heta JA}$	Thermal Resistance, Junction-to-Ambient (Note			40	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Not			0.5	
Packag	e Markin	g and Ordering	Information		
Device I	Marking	Device	Reel Size	Tape width	Quantity
FDS7288N3		FDS7288N3	13"	12mm	2500 units

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics					
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	30			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$ , Referenced to 25°C		25		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24 V, V_{GS} = 0 V$	24 V, V <sub>GS</sub> = 0 V		10	μA
I <sub>GSS</sub>	Gate–Body Leakage	$V_{GS}$ = ± 20 V, $V_{DS}$ = 0 V			± 100	nA
On Char	racteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	1	1.8	3	V
<u>ΔVGS(th)</u> ΔTJ	Gate Threshold Voltage Temperature Coefficient	hold Voltage $I_D = 250 \ \mu$ A, Referenced to $25^{\circ}$ C		-5		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, I_D = 20.5 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 18.5 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 20.5 \text{ A}, T_J = 125^{\circ}\text{C}$		3.8 4.6 5.2	4.5 5.6 7.6	mΩ
<b>g</b> FS	Forward Transconductance	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 20.5 \text{ A}$		106		S
Dynamic C	haracteristics			-		
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 15 V$ , $V_{GS} = 0 V$ ,		3300		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		845		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			230		pF
R <sub>G</sub>	Gate Resistance	$V_{GS}$ = 15 mV, f = 1.0 MHz		1.6		Ω
Switching (	Characteristics (Note 2)			-		-
t <sub>d(on)</sub>	Turn–On Delay Time	$V_{DD} = 15 V, I_D = 1 A,$		12	22	ns
tr	Turn–On Rise Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		11	20	ns
t <sub>d(off)</sub>	Turn–Off Delay Time			45	72	ns
t <sub>f</sub>	Turn–Off Fall Time			32	51	ns
Qg	Total Gate Charge	$V_{DS}$ = 15 V, I <sub>D</sub> = 20.5 A, V <sub>GS</sub> =10 V		49	69	nC
Qg	Total Gate Charge	$V_{DS} = 15 V, I_D = 20.5 A, V_{GS} = 5 V$		26	36	nC
Q <sub>gs</sub>	Gate–Source Charge			8.8		nC
Q <sub>gd</sub>	Gate-Drain Charge			6.7		nC
Drain–S	ource Diode Characteristics	and Maximum Ratings				
ls	Maximum Continuous Drain-Source	e Diode Forward Current			2.5	А
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$ , $I_S = 2.5 A$ (Note 2)		0.70	1.2	V
trr	Diode Reverse Recovery Time	$I_{\rm F} = 20.5  {\rm A},$		36		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	d <sub>iF</sub> /d <sub>t</sub> = 100 A/μs		25		nC

Notes:

1. R<sub>8JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>8JC</sub> is guaranteed by design while R<sub>8CA</sub> is determined by the user's board design.



2. Pulse Test: Pulse Width <  $300\mu$ s, Duty Cycle < 2.0%

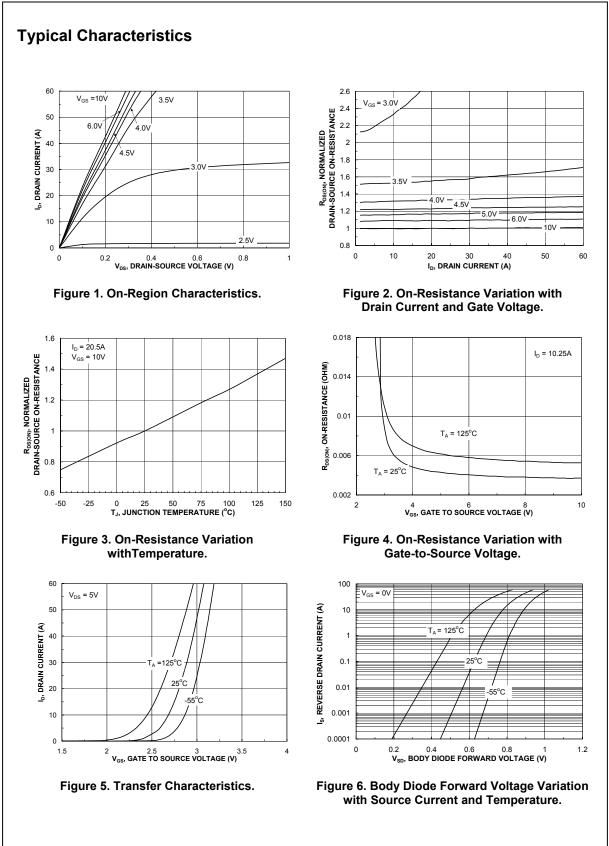
a) 40°C/W when mounted on a 1in<sup>2</sup> pad of 2 oz copper

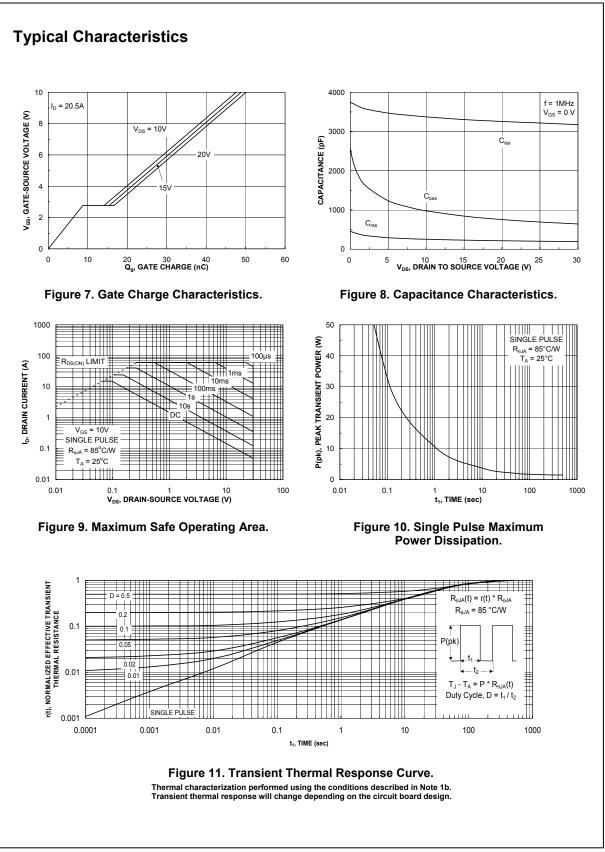


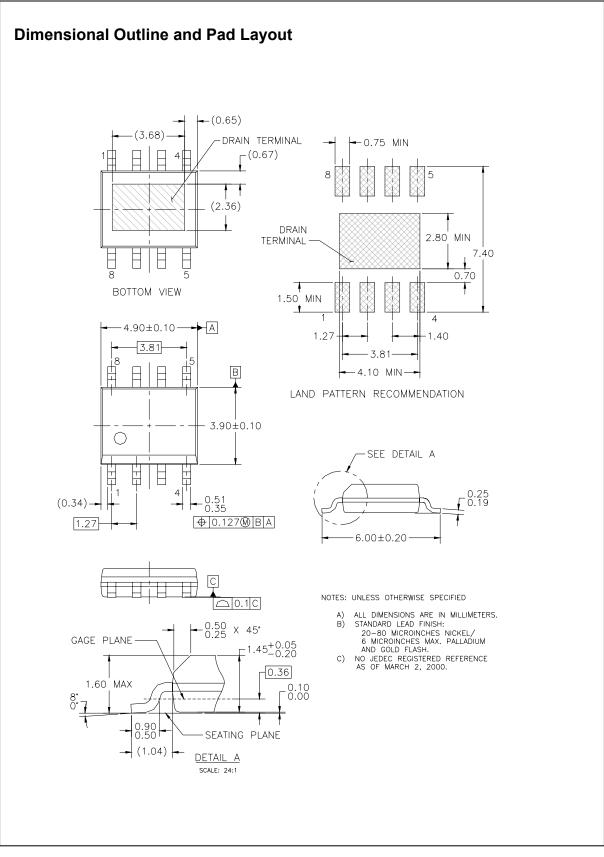
85°C/W when mounted on a minimum pad of 2 oz copper

b)

FDS7288N3 Rev C1 (W)







FDS7288N3 Rev C1 (W)

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